



APPENDIX A
"CLEAN" VERSION OF EACH PARAGRAPH/SECTION/CLAIM
37 C.F.R. § 1.121(b)(ii) AND (c)(i)

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APR 26 2003
TECHNOLOGY CENTER 2800

CLAIMS (with indication of amended or new):

9. (AMENDED) A substrate processing apparatus successively transporting a substrate between a plurality of processing parts thereby performing prescribed processing on said substrate, comprising:

 a transport part successively transporting said substrate between said plurality of processing parts along a prescribed procedure;

 an inspection part capable of performing an inspection including a plurality of inspection contents on said substrate; and

 a procedure setting part capable of incorporating substrate transportation to said inspection part into an arbitrary order position in said procedure, wherein

 said transport part transports each of part or all of a set of plural substrates to be subjected to the same processing to said inspection part where an inspection selected from said plurality of inspection contents of said inspection part is performed so that each of said plurality of inspection contents is performed on at least one and less than all of said set of plural substrates in said inspection part.

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APR 1 2003
TC 1700

APPENDIX B
VERSION WITH MARKINGS TO SHOW CHANGES MADE
37 C.F.R. § 1.121(b)(iii) AND (c)(ii)

CLAIMS:

9. (AMENDED) A substrate processing apparatus successively transporting a substrate between a plurality of processing parts thereby performing prescribed processing on said substrate, comprising:

 a transport part successively transporting said substrate between said plurality of processing parts along a prescribed procedure;

 an inspection part capable of performing an inspection including a plurality of inspection contents on said substrate; and

 a procedure setting part capable of incorporating substrate transportation to said inspection part into an arbitrary order position in said procedure, wherein

 said transport part transports each of part or all of a set of plural substrates to be subjected to the same processing to said inspection part where an inspection selected from said plurality of inspection contents of said inspection part is performed so that each of said plurality of inspection contents is performed on at least one and less than all of said set of plural substrates in said inspection part.